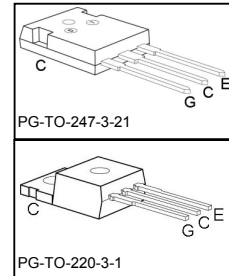
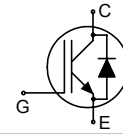


HighSpeed 2-Technology with soft, fast recovery anti-parallel EmCon HE diode

- **Designed for:**
 - SMPS
 - Lamp Ballast
 - ZVS-Converter
- **2nd generation HighSpeed-Technology for 1200V applications offers:**
 - loss reduction in resonant circuits
 - temperature stable behavior
 - parallel switching capability
 - tight parameter distribution
 - E_{off} optimized for $I_C = 3A$
- Qualified according to JEDEC² for target applications
- Pb-free lead plating; RoHS compliant
- Complete product spectrum and PSpice Models : <http://www.infineon.com/igbt/>



Type	V_{CE}	I_C	E_{off}	T_j	Marking	Package
IKW03N120H2	1200V	3A	0.15mJ	150°C	K03H1202	PG-TO-247-3-21
IKP03N120H2	1200V	3A	0.15mJ	150°C	K03H1202	PG-TO-220-3-1

Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage	V_{CE}	1200	V
Triangular collector current	I_C		A
$T_C = 25^\circ\text{C}, f = 140\text{kHz}$		9.6	
$T_C = 100^\circ\text{C}, f = 140\text{kHz}$		3.9	
Pulsed collector current, t_p limited by T_{jmax}	I_{Cpuls}	9.9	
Turn off safe operating area	-	9.9	
$V_{CE} \leq 1200\text{V}, T_j \leq 150^\circ\text{C}$			
Diode forward current	I_F		
$T_C = 25^\circ\text{C}$		9.6	
$T_C = 100^\circ\text{C}$		3.9	
Gate-emitter voltage	V_{GE}	± 20	V
Power dissipation	P_{tot}	62.5	W
$T_C = 25^\circ\text{C}$			
Operating junction and storage temperature	T_j, T_{stg}	-40...+150	°C
Soldering temperature, 1.6mm (0.063 in.) from case for 10s	-	260	

² J-STD-020 and JESD-022

Thermal Resistance

Parameter	Symbol	Conditions	Max. Value	Unit
Characteristic				
IGBT thermal resistance, junction – case	R_{thJC}		2.0	KW
Diode thermal resistance, junction - case	R_{thJCD}		3.2	
Thermal resistance, junction – ambient	R_{thJA}	P-TO-220-3-1 P-TO-247-3-21	62	

Electrical Characteristic, at $T_j = 25\text{ }^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Conditions	Value			Unit
			min.	Typ.	max.	
Static Characteristic						
Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0V, I_C=300\mu A$	1200	-	-	V
Collector-emitter saturation voltage	$V_{CE(sat)}$	$V_{GE} = 15V, I_C=3A$	-	2.2	2.8	
		$T_j=25^\circ\text{C}$	-	2.5	-	
		$T_j=150^\circ\text{C}$	-	2.4	-	
Diode forward voltage	V_F	$V_{GE} = 0, I_F=2A$	-	2.0	2.5	
		$T_j=25^\circ\text{C}$	-	1.75	-	
		$T_j=150^\circ\text{C}$	-	-	-	
Gate-emitter threshold voltage	$V_{GE(th)}$	$I_C=90\mu A, V_{CE}=V_{GE}$	2.1	3	3.9	
Zero gate voltage collector current	I_{CES}	$V_{CE}=1200V, V_{GE}=0V$	-	-	20	μA
		$T_j=25^\circ\text{C}$	-	-	80	
		$T_j=150^\circ\text{C}$	-	-	-	
Gate-emitter leakage current	I_{GES}	$V_{CE}=0V, V_{GE}=20V$	-	-	100	nA
Transconductance	g_{fs}	$V_{CE}=20V, I_C=3A$	-	2	-	S
Dynamic Characteristic						
Input capacitance	C_{iss}	$V_{CE}=25V,$	-	205	-	pF
Output capacitance	C_{oss}	$V_{GE}=0V,$	-	24	-	
Reverse transfer capacitance	C_{riss}	$f=1\text{MHz}$	-	7	-	
Gate charge	Q_{Gate}	$V_{CC}=960V, I_C=3A$ $V_{GE}=15V$	-	22	-	nC
Internal emitter inductance measured 5mm (0.197 in.) from case	L_E	PG-TO-220-3-1	-	7	-	nH
		PG-TO-247-3-21	-	13	-	

Switching Characteristic, Inductive Load, at $T_j=25^\circ\text{C}$

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
IGBT Characteristic						
Turn-on delay time	$t_{d(\text{on})}$	$T_j=25^\circ\text{C}$, $V_{\text{CC}}=800\text{V}$, $I_{\text{C}}=3\text{A}$, $V_{\text{GE}}=15\text{V}/0\text{V}$, $R_{\text{G}}=82\Omega$, $L_{\sigma}^{2)}=180\text{nH}$, $C_{\sigma}^{2)}=40\text{pF}$ Energy losses include "tail" and diode ³⁾ reverse recovery.	-	9.2	-	ns
Rise time	t_{r}		-	5.2	-	
Turn-off delay time	$t_{d(\text{off})}$		-	281	-	
Fall time	t_{f}		-	29	-	mJ
Turn-on energy	E_{on}		-	0.14	-	
Turn-off energy	E_{off}		-	0.15	-	
Total switching energy	E_{ts}		-	0.29	-	
Anti-Parallel Diode Characteristic						
Diode reverse recovery time	t_{rr}	$T_j=25^\circ\text{C}$, $V_{\text{R}}=800\text{V}$, $I_{\text{F}}=3\text{A}$, $R_{\text{G}}=82\Omega$	-	42	-	ns
Diode reverse recovery charge	Q_{rr}		-	0.23	-	μC
Diode peak reverse recovery current	I_{rrm}		-	10.3	-	A
Diode current slope	di_{F}/dt		-	993	-	$\text{A}/\mu\text{s}$
Diode peak rate of fall of reverse recovery current during t_{b}	di_{rr}/dt		-	1180	-	

Switching Characteristic, Inductive Load, at $T_j=150^\circ\text{C}$

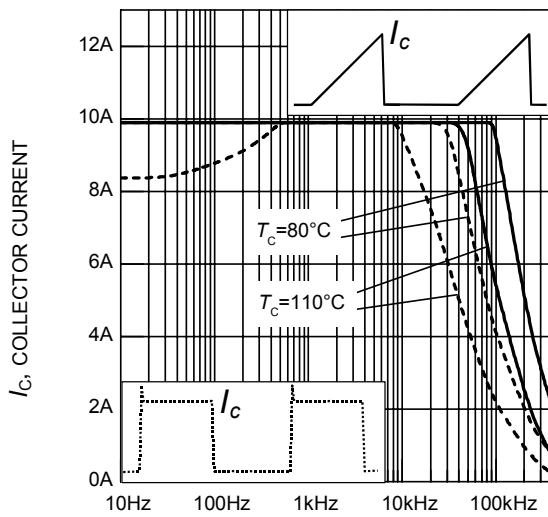
Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
IGBT Characteristic						
Turn-on delay time	$t_{d(\text{on})}$	$T_j=150^\circ\text{C}$ $V_{\text{CC}}=800\text{V}$, $I_{\text{C}}=3\text{A}$, $V_{\text{GE}}=15\text{V}/0\text{V}$, $R_{\text{G}}=82\Omega$, $L_{\sigma}^{2)}=180\text{nH}$, $C_{\sigma}^{2)}=40\text{pF}$ Energy losses include "tail" and diode ³⁾ reverse recovery.	-	9.4	-	ns
Rise time	t_{r}		-	6.7	-	
Turn-off delay time	$t_{d(\text{off})}$		-	340	-	
Fall time	t_{f}		-	63	-	mJ
Turn-on energy	E_{on}		-	0.22	-	
Turn-off energy	E_{off}		-	0.26	-	
Total switching energy	E_{ts}		-	0.48	-	
Anti-Parallel Diode Characteristic						
Diode reverse recovery time	t_{rr}	$T_j=150^\circ\text{C}$ $V_{\text{R}}=800\text{V}$, $I_{\text{F}}=3\text{A}$, $R_{\text{G}}=82\Omega$	-	125	-	ns
Diode reverse recovery charge	Q_{rr}		-	0.51	-	μC
Diode peak reverse recovery current	I_{rrm}		-	12	-	A
Diode current slope	di_{F}/dt		-	829	-	$\text{A}/\mu\text{s}$
Diode peak rate of fall of reverse recovery current during t_{b}	di_{rr}/dt		-	540	-	

²⁾ Leakage inductance L_{σ} and stray capacity C_{σ} due to dynamic test circuit in figure E

³⁾ Commutation diode from device IKP03N120H2

Switching Energy ZVT, Inductive Load

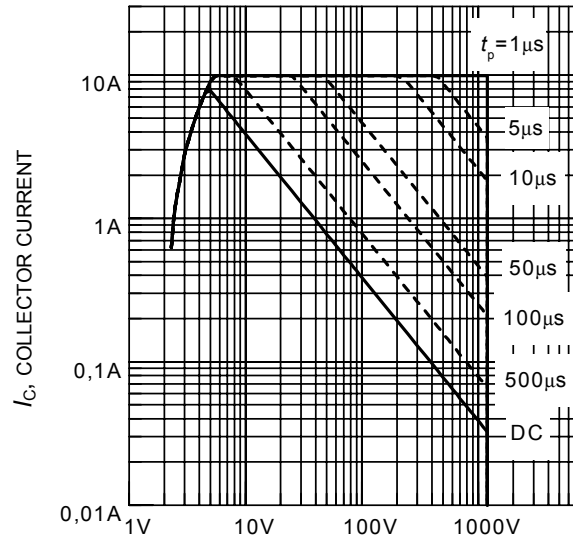
Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
IGBT Characteristic						
Turn-off energy	E_{off}	$V_{CC}=800V,$ $I_C=3A,$ $V_{GE}=15V/0V,$ $R_G=82\Omega,$ $C_r^{2)}=4nF$ $T_j=25^\circ C$ $T_j=150^\circ C$	-	0.05	-	mJ
			-	0.09	-	



f , SWITCHING FREQUENCY

Figure 1. Collector current as a function of switching frequency

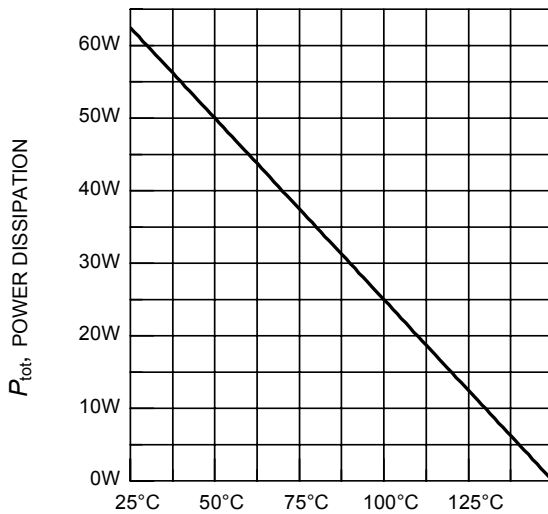
($T_j \leq 150^\circ\text{C}$, $D = 0.5$, $V_{CE} = 800\text{V}$,
 $V_{GE} = +15\text{V}/0\text{V}$, $R_G = 82\Omega$)



V_{CE} , COLLECTOR-EMITTER VOLTAGE

Figure 2. Safe operating area

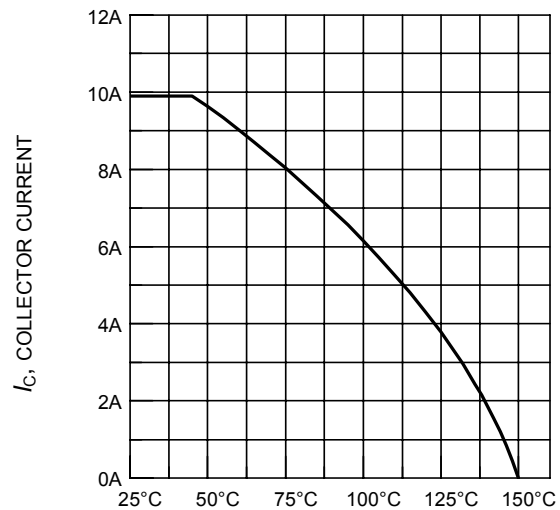
($D = 0$, $T_C = 25^\circ\text{C}$, $T_j \leq 150^\circ\text{C}$)



T_C , CASE TEMPERATURE

Figure 3. Power dissipation as a function of case temperature

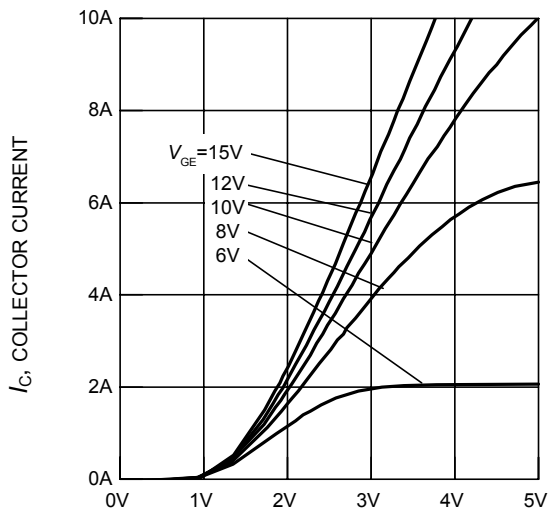
($T_j \leq 150^\circ\text{C}$)



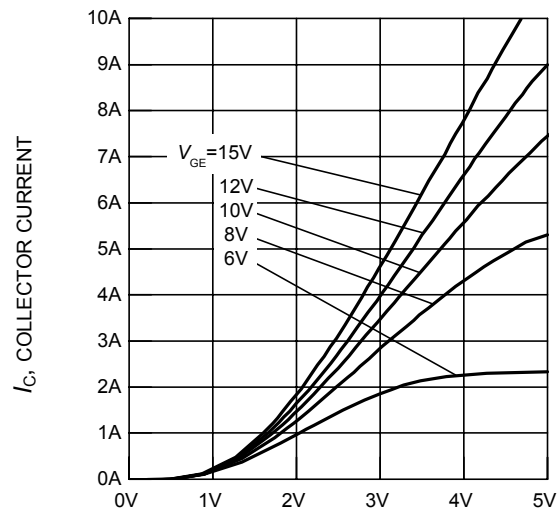
T_C , CASE TEMPERATURE

Figure 4. Collector current as a function of case temperature

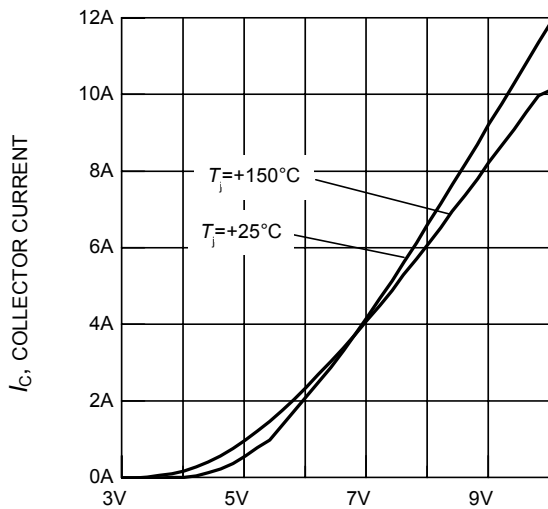
($V_{GE} \leq 15\text{V}$, $T_j \leq 150^\circ\text{C}$)



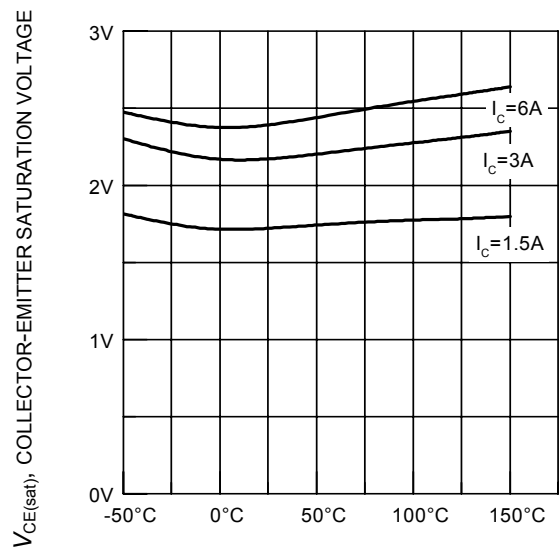
V_{CE} , COLLECTOR-EMITTER VOLTAGE
Figure 5. Typical output characteristics
($T_j = 25^\circ\text{C}$)



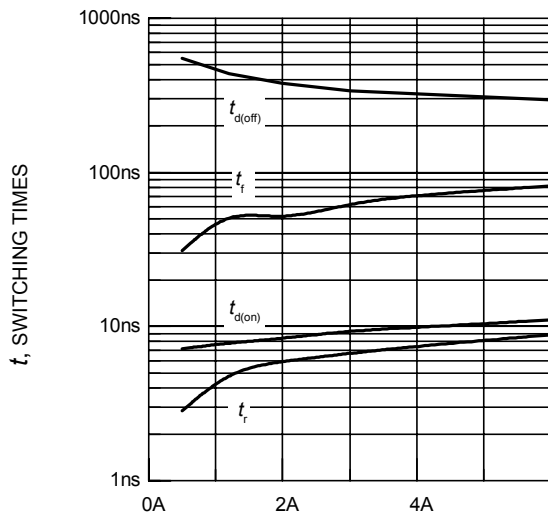
V_{CE} , COLLECTOR-EMITTER VOLTAGE
Figure 6. Typical output characteristics
($T_j = 150^\circ\text{C}$)



V_{GE} , GATE-EMITTER VOLTAGE
Figure 7. Typical transfer characteristics
($V_{CE} = 20\text{V}$)



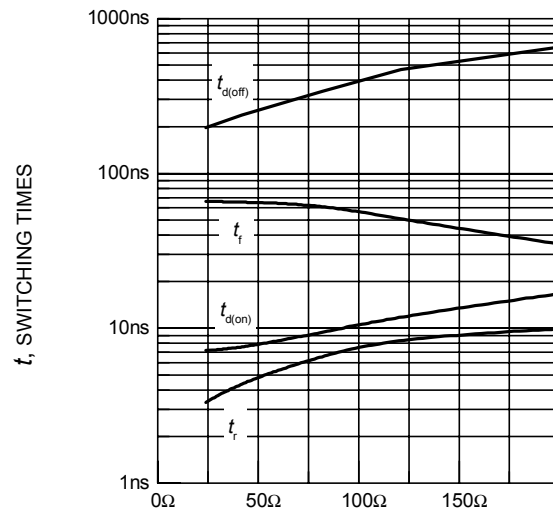
T_j , JUNCTION TEMPERATURE
Figure 8. Typical collector-emitter saturation voltage as a function of junction temperature
($V_{GE} = 15\text{V}$)



I_C , COLLECTOR CURRENT

Figure 9. Typical switching times as a function of collector current

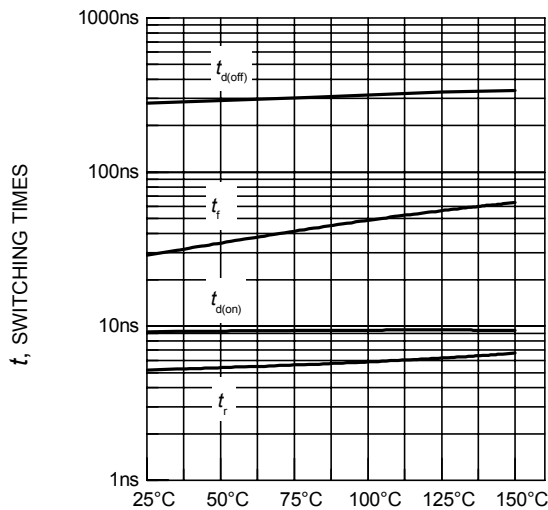
(inductive load, $T_j = 150^\circ\text{C}$, $V_{CE} = 800\text{V}$, $V_{GE} = +15\text{V}/0\text{V}$, $R_G = 82\Omega$, dynamic test circuit in Fig.E)



R_G , GATE RESISTOR

Figure 10. Typical switching times as a function of gate resistor

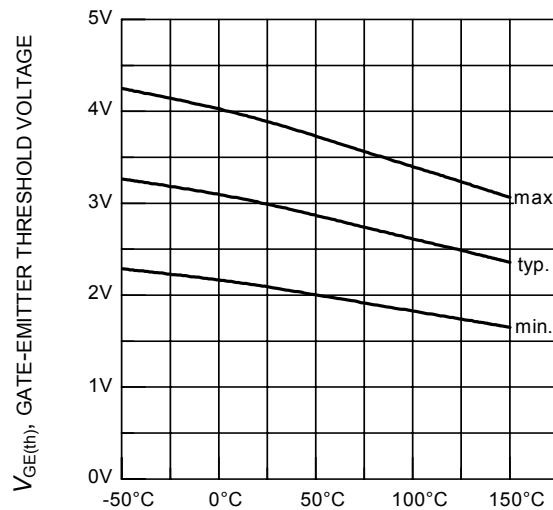
(inductive load, $T_j = 150^\circ\text{C}$, $V_{CE} = 800\text{V}$, $V_{GE} = +15\text{V}/0\text{V}$, $I_C = 3\text{A}$, dynamic test circuit in Fig.E)



T_j , JUNCTION TEMPERATURE

Figure 11. Typical switching times as a function of junction temperature

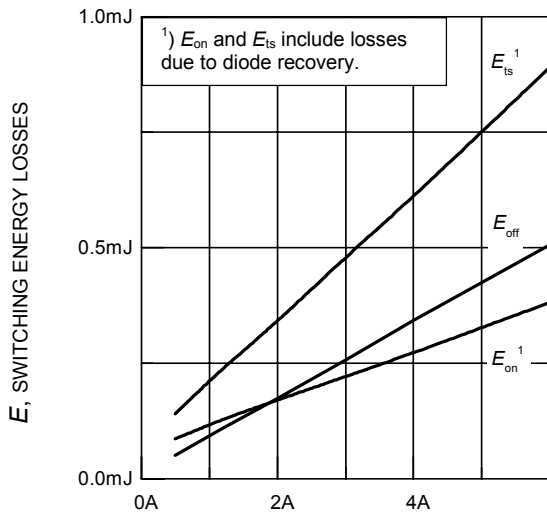
(inductive load, $V_{CE} = 800\text{V}$, $V_{GE} = +15\text{V}/0\text{V}$, $I_C = 3\text{A}$, $R_G = 82\Omega$, dynamic test circuit in Fig.E)



T_j , JUNCTION TEMPERATURE

Figure 12. Gate-emitter threshold voltage as a function of junction temperature

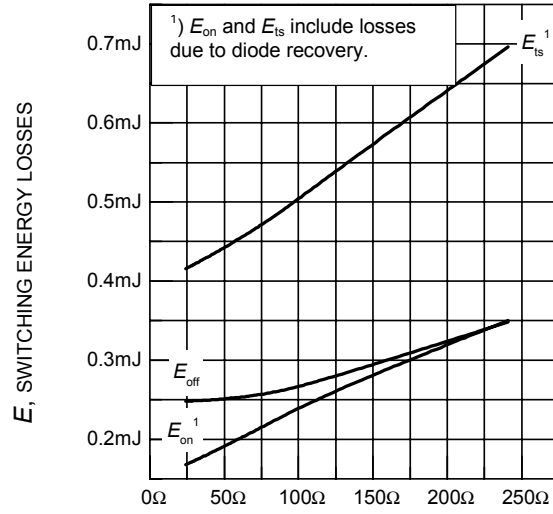
($I_C = 0.09\text{mA}$)



I_C , COLLECTOR CURRENT

Figure 13. Typical switching energy losses as a function of collector current

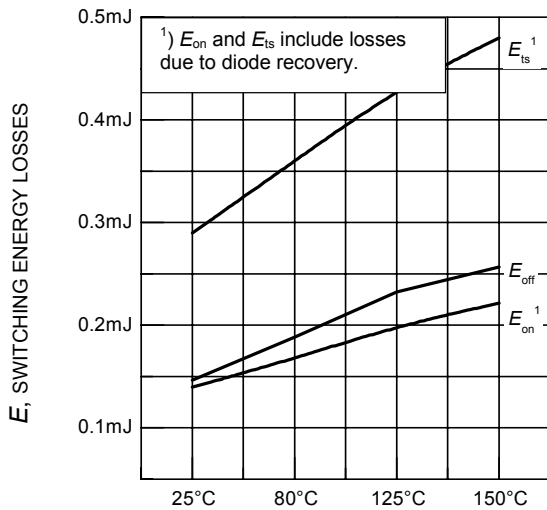
(inductive load, $T_j = 150^\circ\text{C}$, $V_{CE} = 800\text{V}$, $V_{GE} = +15\text{V}/0\text{V}$, $R_G = 82\Omega$, dynamic test circuit in Fig.E)



R_G , GATE RESISTOR

Figure 14. Typical switching energy losses as a function of gate resistor

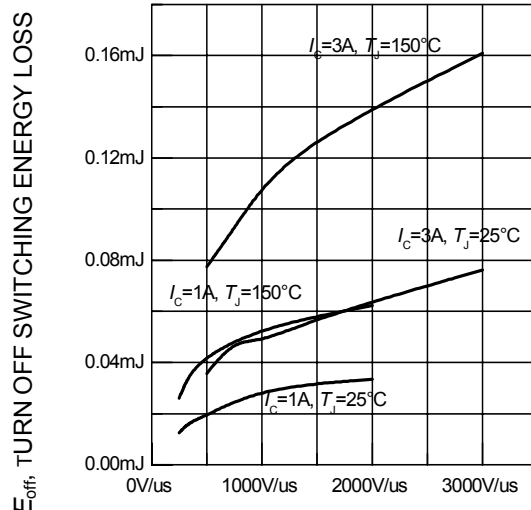
(inductive load, $T_j = 150^\circ\text{C}$, $V_{CE} = 800\text{V}$, $V_{GE} = +15\text{V}/0\text{V}$, $I_C = 3\text{A}$, dynamic test circuit in Fig.E)



T_j , JUNCTION TEMPERATURE

Figure 15. Typical switching energy losses as a function of junction temperature

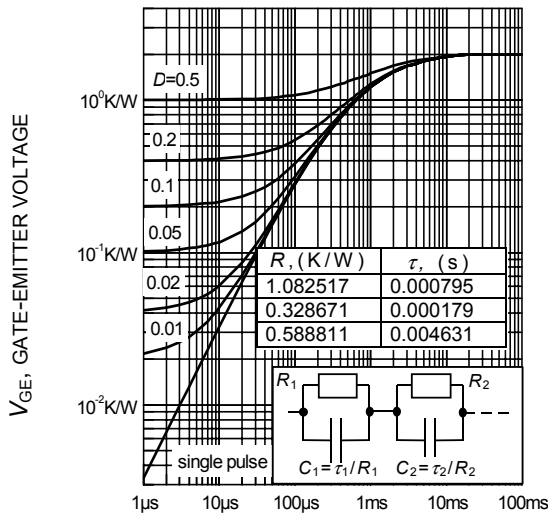
(inductive load, $V_{CE} = 800\text{V}$, $V_{GE} = +15\text{V}/0\text{V}$, $I_C = 3\text{A}$, $R_G = 82\Omega$, dynamic test circuit in Fig.E)



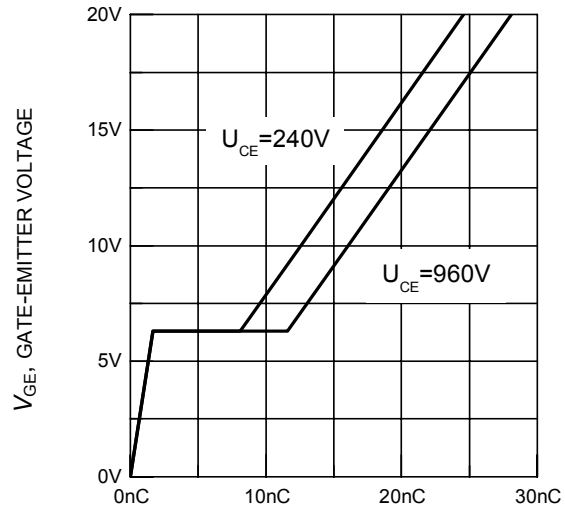
dv/dt , VOLTAGE SLOPE

Figure 16. Typical turn off switching energy loss for soft switching

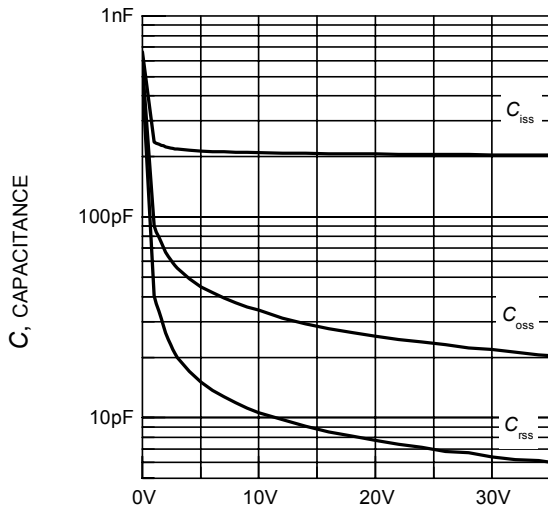
(dynamic test circuit in Fig. E)



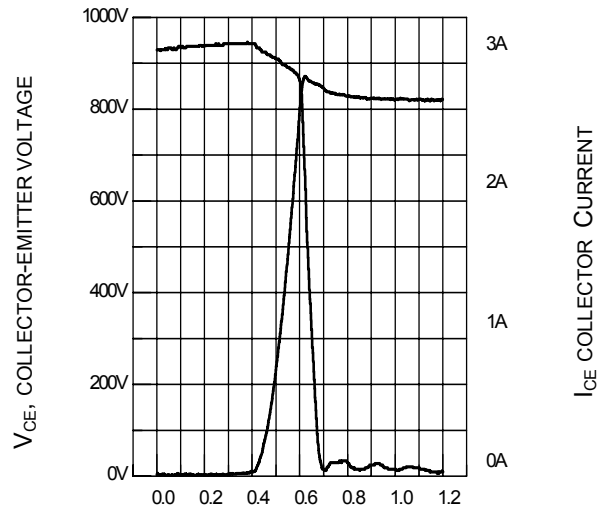
Q_{GE} , GATE CHARGE
Figure 17. Typical gate charge
($I_C = 3A$)



Q_{GE} , GATE CHARGE
Figure 17. Typical gate charge
($I_C = 3A$)



V_{CE} , COLLECTOR-EMITTER VOLTAGE
Figure 18. Typical capacitance as a function of collector-emitter voltage
($V_{GE} = 0V$, $f = 1MHz$)



t_p , PULSE WIDTH
Figure 20. Typical turn off behavior, hard switching
($V_{GE} = 15/0V$, $R_G = 82\Omega$, $T_j = 150^\circ C$,
Dynamic test circuit in Figure E)

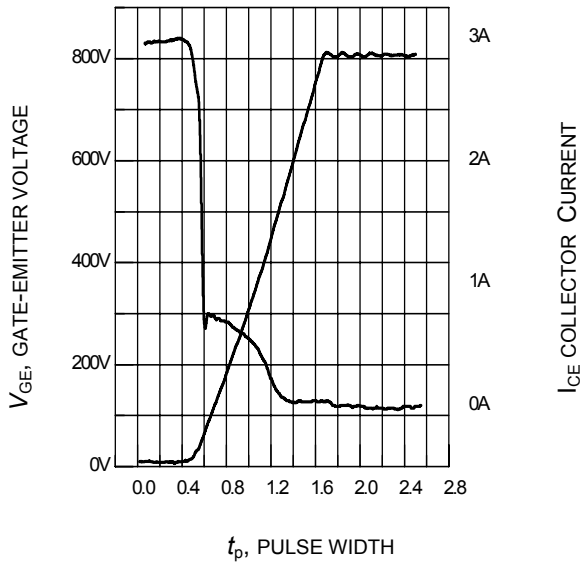


Figure 21. Typical turn off behavior, soft switching
($V_{GE}=15/0V$, $R_G=82\Omega$, $T_J = 150^\circ C$,
Dynamic test circuit in Figure E)

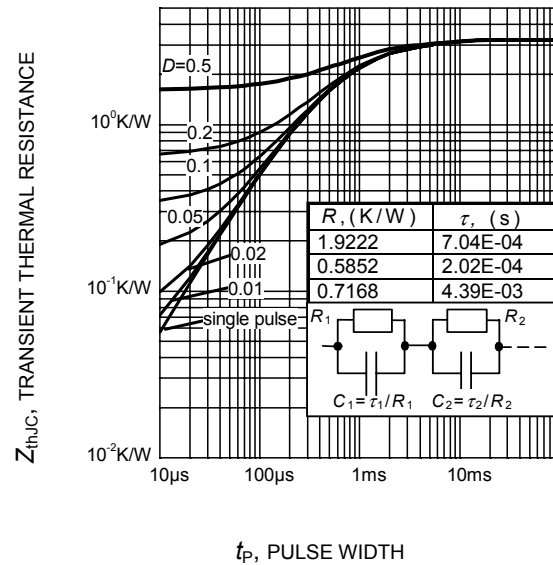


Figure 22. Diode transient thermal impedance as a function of pulse width
($D=t_p/T$)

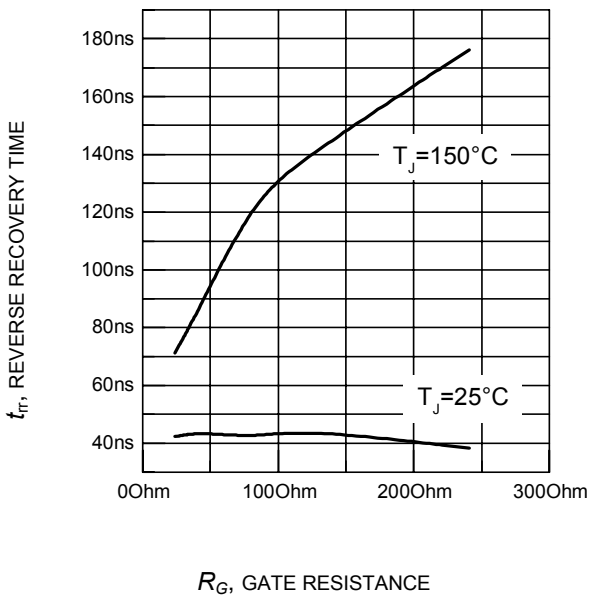


Figure 23. Typical reverse recovery time as a function of diode current slope
($V_R=800V$, $I_F=3A$,
Dynamic test circuit in Figure E)

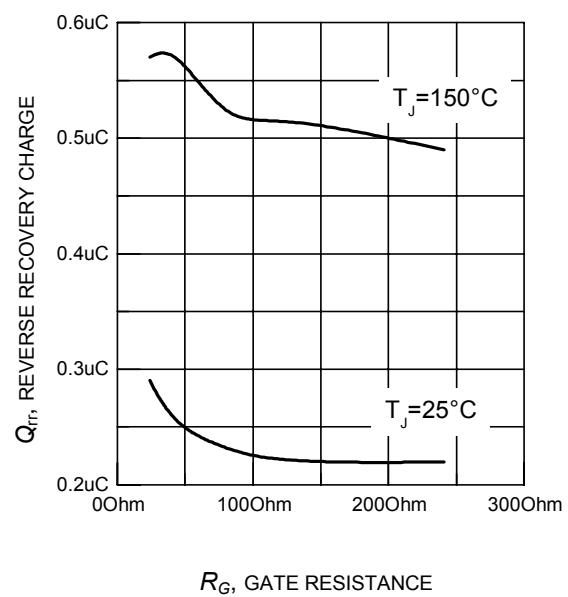
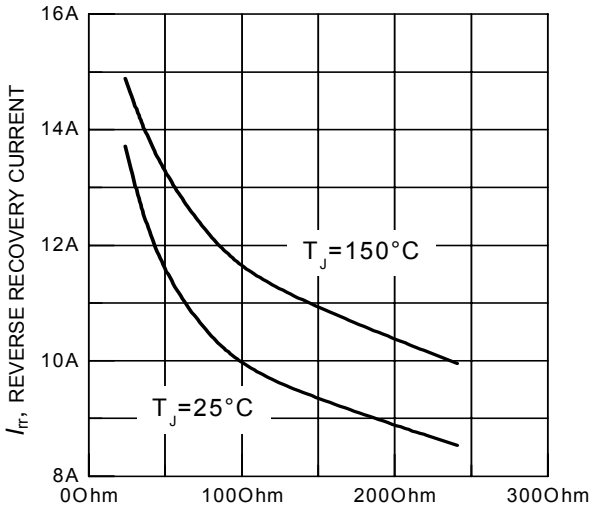
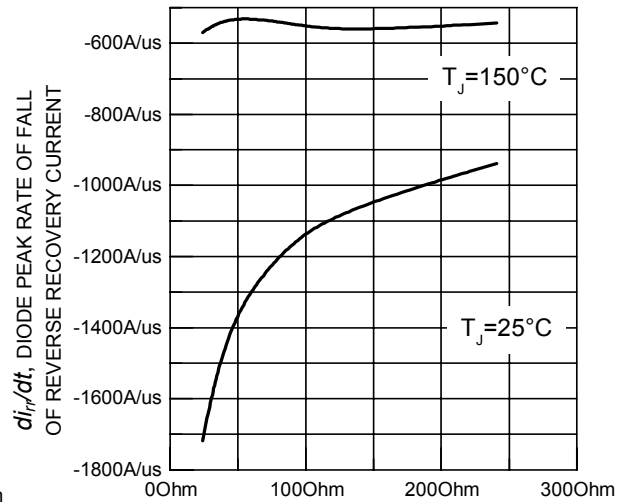


Figure 24. Typical reverse recovery charge as a function of diode current slope
($V_R=800V$, $I_F=3A$,
Dynamic test circuit in Figure E)



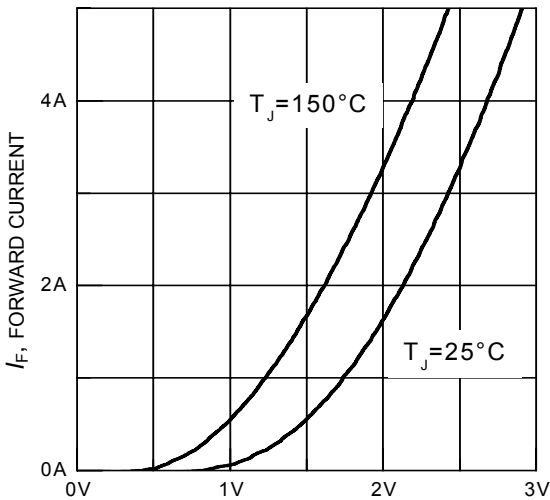
R_G , GATE RESISTANCE

Figure 25. Typical reverse recovery current as a function of diode current slope
($V_R=800V$, $I_F=3A$,
Dynamic test circuit in Figure E)



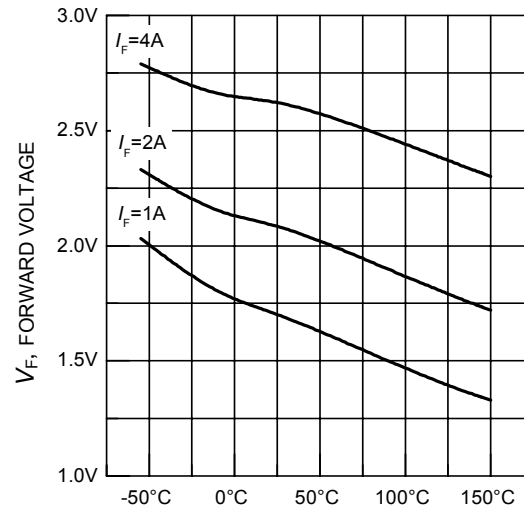
R_G , GATE RESISTANCE

Figure 26. Typical diode peak rate of fall of reverse recovery current as a function of diode current slope
($V_R=800V$, $I_F=3A$,
Dynamic test circuit in Figure E)



V_F , FORWARD VOLTAGE

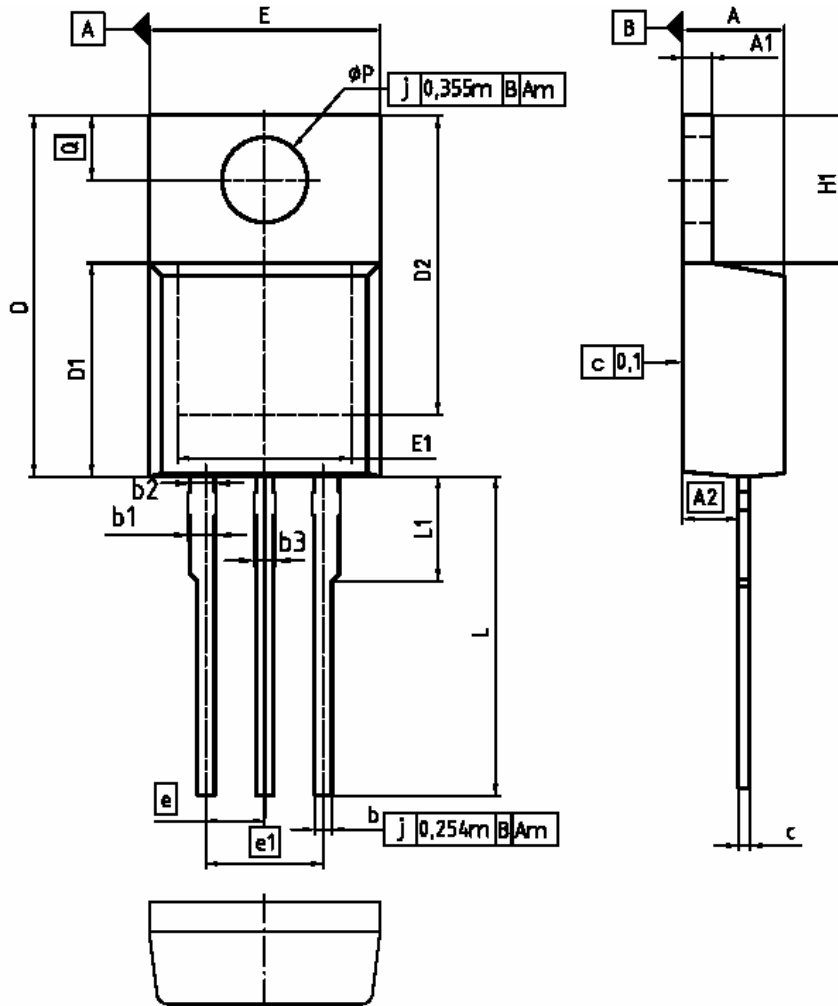
Figure 27. Typical diode forward current as a function of forward voltage



T_J , JUNCTION TEMPERATURE

Figure 28. Typical diode forward voltage as a function of junction temperature

PG-TO220-3-1



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.30	4.57	0.169	0.180
A1	1.17	1.40	0.046	0.055
A2	2.15	2.72	0.085	0.107
b	0.65	0.66	0.026	0.024
b1	0.95	1.40	0.037	0.055
b2	0.65	1.15	0.026	0.045
b3	0.65	1.15	0.026	0.045
c	0.33	0.60	0.013	0.024
D	14.81	15.95	0.583	0.628
D1	8.61	9.45	0.336	0.372
D2	12.18	13.10	0.480	0.518
E	8.70	10.36	0.342	0.408
E1	6.60	8.60	0.260	0.339
e	2.54		0.100	
e1	5.08		0.200	
N	3		3	
H1	5.90	8.90	0.232	0.272
L	13.00	14.00	0.512	0.551
L1	-	4.80	-	0.189
ϕP	3.80	3.89	0.142	0.153
Q	2.60	3.00	0.102	0.118

DOCUMENT NO.
Z8B00003318

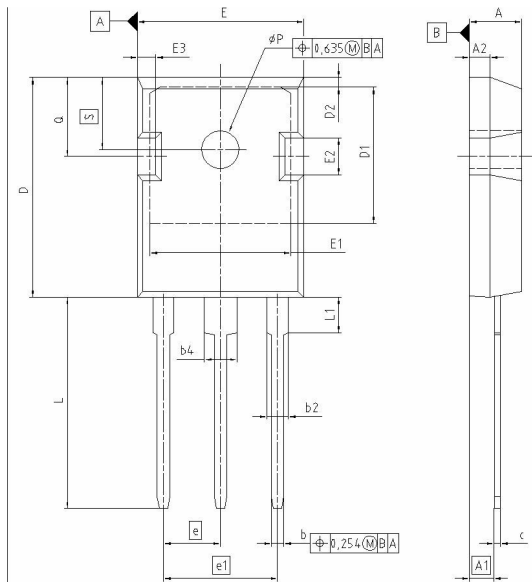
SCALE

EUROPEAN PROJECTION

ISSUE DATE
23-08-2007

REVISION
05

PG-TO247-3-21



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.903	5.157	0.193	0.203
A1	2.273	2.527	0.092	0.096
A2	1.853	2.107	0.075	0.081
b	1.073	1.327	0.047	0.052
b2	1.903	2.386	0.075	0.094
b4	2.870	3.454	0.113	0.136
c	0.549	0.752	0.024	0.030
D	20.823	21.077	0.820	0.830
D1	17.323	17.831	0.682	0.702
D2	1.063	1.317	0.042	0.052
E	15.773	16.027	0.621	0.631
E1	13.893	14.147	0.547	0.557
E2	3.683	3.937	0.145	0.155
E3	1.683	1.937	0.066	0.076
e	5.450		0.215	
e1	10.900		0.430	
N	3		3	
L	20.053	20.307	0.789	0.799
L1	4.168	4.472	0.164	0.176
ϕP	3.559	3.661	0.140	0.144
Q	5.493	5.747	0.216	0.226
S	6.043	6.297	0.238	0.248

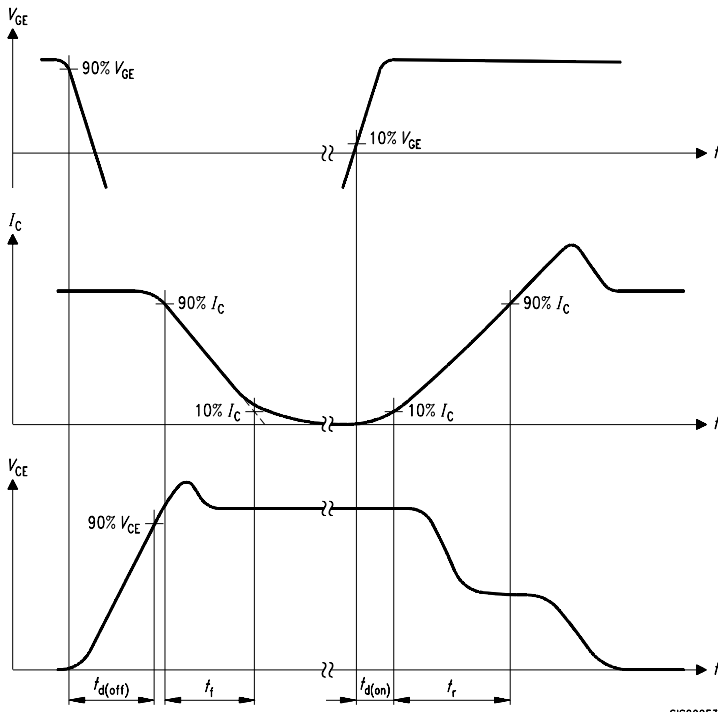


Figure A. Definition of switching times

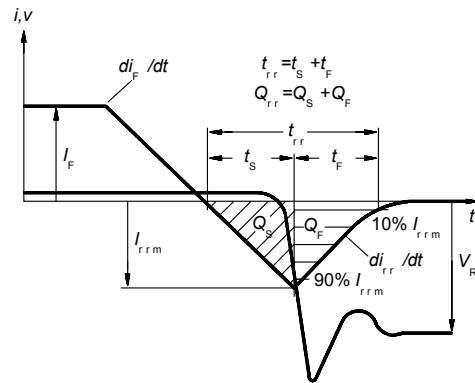


Figure C. Definition of diodes switching characteristics

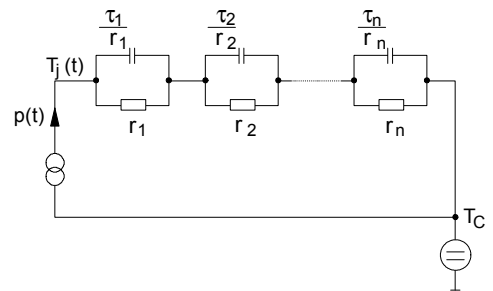


Figure D. Thermal equivalent circuit

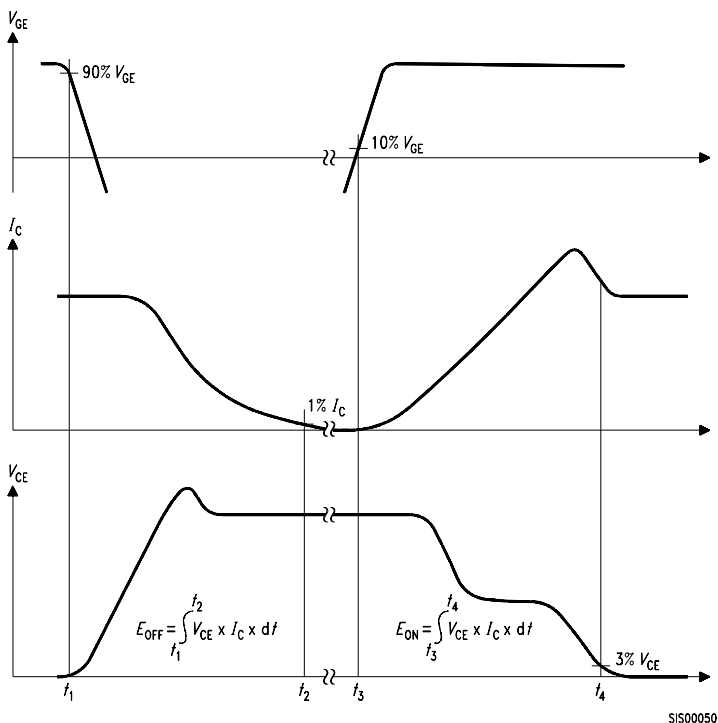


Figure B. Definition of switching losses

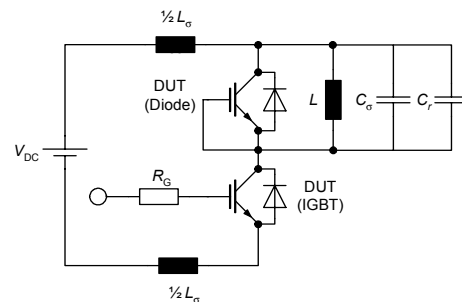


Figure E. Dynamic test circuit
Leakage inductance $L_{\sigma} = 180\text{nH}$,
Stray capacitor $C_{\sigma} = 40\text{pF}$,
Relief capacitor $C_r = 4\text{nF}$ (only for ZVT switching)

Edition 2006-01

Published by
Infineon Technologies AG
81726 München, Germany

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